

IFW
#

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2815
Serial No. : 10/693,491 Examiner : Paul E. Brock II
Filed : October 27, 2003 Confirmation No.: 3131
Title : SEMICONDUCTOR DEVICE AND FABRICATION METHOD THEREOF

MAIL STOP AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants would like to bring the Examiner's attention to the references listed on the attached form PTO-1449. It is respectfully requested each of the references listed on the attached form PTO-1449 be considered by the Examiner and that the document be initialed and returned to the undersigned.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of C.F.R. § 1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: February 1, 2005



John F. Hayden
Reg. No. 37,640

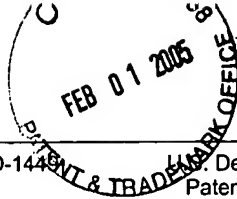
Customer No. 26171
Fish & Richardson P.C.
1425 K Street, N.W., 11th Floor
Washington, DC 20005-3500
Telephone: (202) 783-5070
Facsimile: (202) 783-2331

40264460.doc

02/03/2005 AWONDAF1 00000170 10693491

01 FC:1806

180.00 OP



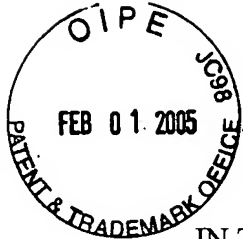
Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-097002	Application No. 10/693,491
	Applicant Shunpei Yamazaki et al.		
	Filing Date October 27, 2003	Group Art Unit 2815	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002/0001886 A1	01/03/2002	Ohtani			07/27/2001
	AB	2004/0115851 A1	06/17/2004	Tanaka et al.			07/15/2003
	AC	6,277,679 B1	08/21/2001	Ohtani			11/24/1999
	AD	6,635,505 B2	10/21/2003	Tanaka et al.			11/18/2002
	AE	6,489,952 B1	12/03/2002	Tanaka et al.			11/12/1999
	AF	6,512,271 B1	01/28/2003	Yamazaki et al.			11/16/1999
	AG	6,518,594 B1	02/11/2003	Nakajima et al.			11/16/1999
	AH	6,791,112 B2	09/14/2004	Yamazaki et al.			10/01/2002
	AI	6,803,601 B2	10/12/2004	Nakajima			05/06/2002
	AJ	6,815,273 B2	11/09/2004	Nakajima et al.			11/12/2002

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AK							
	AL							
	AM							
	AN							
	AO							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AP	
	AQ	
	AR	
	AS	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2815
Serial No. : 10/693,491 Examiner : Paul E. Brock II
Filed : October 27, 2003 Confirmation No.: 3131
Title : SEMICONDUCTOR DEVICE AND FABRICATION METHOD THEREOF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

REQUEST FOR INITIALED PTO FORMS 1449

Upon reviewing the file, applicants noted that they have not received an initialed copy of the enclosed PTO Forms 1449 that accompanied an information disclosure statement filed with the application on October 27, 2003 and an information disclosure statement filed July 16, 2004.

Applicants' records show that these information disclosure statements complied with 37 CFR 1.97. Thus, it is respectfully requested that the examiner consider the listed references and initial and return these forms as soon as possible.

Respectfully submitted,

Date: February 1, 2005



John F. Hayden
Reg. No. 37,640

Fish & Richardson P.C.
1425 K Street, N.W., 11th Floor
Washington, DC 20005-3500
(202) 783-5070 telephone
(202) 783-2331 facsimile

FEB 01 2005

Sheet 1 of 1

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-097002	Application No. 10/693,491
	Applicant Shunpei Yamazaki et al.		
	Filing Date October 27, 2003	Group Art Unit 2811	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002/0139980	10/03/2002	YAMAZAKI			
	AB	2002/0142554	10/03/2002	NAKAJIMA			
	AC	2002/0149016	10/17/2002	YAMAZAKI et al.			
	AD	2003/0122132	07/03/2003	YAMAZAKI			
	AE	2003/0211662	11/13/2003	YAMAZAKI et al.			
	AF	6,399,960	06/04/2002	YAMAZAKI et al.			
	AG	6,420,758	07/16/2002	NAKAJIMA			
	AH	6,501,098	12/31/2002	YAMAZAKI			
	AI	6,586,766	07/01/2003	YAMAZAKI et al.			
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	Australian Patent Office Search Report and Written Opinion of Counterpart Singapore Patent Application No. 200201696-2, February 16, 2004, 9 pages
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

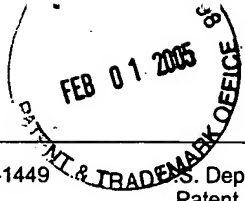
Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-097002	Application No. New Divisional Application
	Applicant Shunpei Yamazaki et al.		
	Filing Date October 27, 2003	Group Art Unit Unknown	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,276,347	01/1994	Wei et al.			
	AB	5,643,826	07/01/1997	Ohtani et al.			
	AC	5,923,962	07/13/1999	Ohtani et al.			
	AD	6,031,290	02/29/2000	Miyazaki et al.			
	AE	6,150,249	11/2000	Lee et al.			
	AF	6,165,824	12/26/2000	Takano et al.			
	AG	6,285,042 B1	09/04/2001	Ohtani et al.			
	AH	6,335,541 B1	01/01/2002	Ohtani et al.			
	AI	6,365,917	04/02/2002	Yamazaki			
	AJ	6,399,960	06/2002	Yamazaki et al.			
	AK	6,420,758	07/2002	Nakajima			
	AL	6,475,836	11/05/2002	Suzawa et al.			
	AM	6,501,098	12/2002	Yamazaki			
	AN	6,515,336	02/04/2003	Suzawa et al.			
	AO	US 2001/0030322 A1	10/18/2001	Yamazaki et al.			
	AP	US 2001/0030342 A1	10/2001	Ohnishi et al.			
	AQ	US 2001/0049197 A1	12/06/2001	Yamazaki et al.			
	AR	US 2001/0052950 A1	12/20/2001	Yamazaki et al.			
	AS	US 2001/0055841 A1	12/27/2001	Yamazaki et al.			
	AT	US 2002/0006705 A1	01/17/2002	Suzawa et al.			
	AU	US 2002/0013022 A1	01/31/2002	Yamazaki et al.			
	AV	US 2002/0016028 A1	02/07/2002	Arao et al.			
	AW	US 2002/0017685 A1	02/14/2002	Kasahara et al.			
	AX	US 2002/0070382 A1	06/13/2002	Yamazaki et al.			
	AY	US 2002/0110941 A1	08/15/2002	Yamazaki et al.			
	AZ	US 2002/0158288 A1	10/31/2002	Yamazaki et al.			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))				Attorney's Docket No. 12732-097002		Application No. New Divisional Application		
				Applicant Shunpei Yamazaki et al.				
				Filing Date October 27, 2003		Group Art Unit Unknown		
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No	
	AAA	06-148685	05/27/1994	JAPAN			ABS	
	ABB	07-130652	05/19/1995	JAPAN			ABS	
	ACC	07-235680	09/05/1995	JAPAN			ABS	
	ADD	08-274336	10/18/1996	JAPAN			FULL	
	AEE	10-247735	09/14/1998	JAPAN			ABS	
	AFF	0 082 012 A2	06/22/1983	EUROPE				

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AGG	
	AHH	
	AII	
	AJJ	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	